

METHOD, SENSING DEVICE AND OPTICAL POINTING DEVICE INCLUDING A
SENSING DEVICE FOR COMPARING LIGHT INTENSITY BETWEEN PIXELS

FIELD OF THE INVENTION

The present invention generally relates to pointing devices, in particular for controlling the position of a cursor on a screen, such as the display of a personal computer, workstation or other computing devices having a graphic user interface. Such pointing devices may for instance include mice, trackballs and other computer peripherals for controlling the position of a cursor on a display screen.

5 The present invention more particularly relates to the field of optical pointing devices which comprise an optical sensing device including a photodetector array for measuring the varying intensity pattern of a portion of a surface which is illuminated with radiation and for extracting information about the relative motion between the
10 photodetector array and the illuminated portion of the surface.

BACKGROUND OF THE INVENTION

Optical pointing devices are already known in the art. U.S. Patent No. 5,288,993, which is incorporated herein by reference, for instance discloses a cursor pointing device utilizing a photodetector array and an illuminated target ball having randomly distributed speckles. U.S. Patent No. 5,703,356 (related to the
15 above-mentioned U.S. Patent No. 5,288,993), which is also incorporated herein by reference, further discloses (in reference to Figures 23A and 23B of this document) an optical cursor pointing device in the form of a mouse which does not require a ball and wherein light is reflected directly from the surface over which the pointing device is moved.
20 The imaging technique used in above-cited U.S. patents No. 5,288,993 and 5,703,356 in order to extract motion-related information is based on a so-called "Edge Motion Detection" technique. This "Edge Motion Detection" technique essentially consists in a determination of the movement of edges (i.e. a difference between the intensity of pairs of pixels) in the image detected by the photodetector array. Edges
25 are defined as spatial intensity differences between two pixels of the photodetector array. The relative motion of each of these edges is tracked and measured so as to determine an overall displacement measurement which is representative of the relative movement between the photodetector array and the illuminated portion of the surface.

More particularly, according to U.S. Patent No. 5,288,993, edges are determined between pairs of pixels aligned along a first axis of the photodetector array (for example in each row of the photodetector array) and between pairs of pixels aligned along a second axis of the photodetector array (for example in each column of the photodetector array). Figure 10 depicts three pixels of the photodetector array, a first pixel or current pixel P, a second pixel Pright aligned with the first pixel P along a first axis 101, and a third pixel Pup aligned with the first pixel P along a second axis 102. Pixels Pright and Pup are shown as being disposed on the right side and top side of pixel P for the purpose of explanation only. It will be appreciated that axes 101 and 102 may be orthogonal (as shown) or alternatively non orthogonal. It will also be appreciated that the pixels are not necessarily disposed so as to form a regular array having rows and columns. Other suitable arrangements may very well be envisaged.

For the purpose of simplification, the pixels of Figure 10 are either shown as being white or black, a black pixel denoting an illuminated pixel. In this case, pixel P is illuminated and first and second edge conditions Ex, Ey exist respectively between pixels P and Pright along the first axis 101 and between pixels P and Pup along the second axis 102.

According to U.S. Patent No. 5,288,993 and U.S. Patent No. 5,703,356, the displacement measurement is evaluated, on the one hand, based on a normalized difference between the number of edges Ex which move in a first direction along the first axis 101 and edges Ex which move in the opposite direction along the first axis 101 (for example edges which move from left to right and right to left in each row of the photodetector array), and, on the other hand, based on a normalized difference between the number of edges Ey which move in a first direction along the second axis 102 and edges Ey which move in the opposite direction along the second axis 102 (for example edges which move downwards and upwards in each column of the photodetector array).

Relative motion of edges is determined by comparing the position of these edges in the photodetector array at a first point in time with the position of edges in the photodetector array at a subsequent point in time. The optical pointing device thus typically comprises a light source (such as an infrared LED) which intermittently illuminates the portion of the surface in accordance with a determined sequence, and the pixel outputs of the photodetector array are sampled in accordance with the determined sequence to provide two successive sets of edge data that are compared to each other in order to determine a relative motion measurement.

According to one embodiment of U.S. Patent No. 5,288,993 and U.S. Patent No. 5,703,356 a differential technique is advantageously used in order to determine an

edge condition between two pixels. According to this embodiment, an edge is defined as laying between two pixels if the ratio of intensities of the two photosensitive elements is larger than a determined level. An edge may thus be defined mathematically by the following Boolean expression :

5

$$\begin{aligned} & \text{Intensity[PIXEL 1]} > K \text{ Intensity[PIXEL 2]} \\ & \text{OR} \\ & K \text{ Intensity[PIXEL 1]} < \text{Intensity[PIXEL 2]} \end{aligned} \quad (1)$$

10 where K is the selected scaling factor.

It will be appreciated that the first and second parts of the above expression, taken individually, each define an edge condition between the two pixels.

According to U.S. Patent No. 5,703,356, the differences of intensities or edges between pixels is sensed as a difference in currents. More particularly, Figure 17A of 15 this document shows a differential current sensor for detecting an edge condition between two pixels. Figure 1 of the present specification illustrates this differential current sensor. In this example, the current i_{out} generated by the photosensitive element 1000 of the pixel is applied (after charge amplification by means of the charge amplifier 1705) on a input branch 1710A-B of a current mirror comprising eight output 20 branches 1710, 1715, 1720, 1725, 1730, 1735, 1740 and 1745, four of which (output branches 1710, 1715, 1730 and 1735) output a non-scaled image of the input current i_{out} . The other four output branches 1720, 1725, 1740, 1745 output a scaled image of the input current i_{out} (K times the input current i_{out}), the scaling factor K being defined by an adequate choice of the dimensions of the corresponding transistors of the 25 current mirror. Two output branches 1715, 1720 supply the image i_{o1l} and the scaled image i_{o1Kl} of the input current i_{out} to the pixel on the left. Similarly two output branches 1735, 1740 supply the image i_{o1d} and the scaled image i_{o1Kd} of the input current i_{out} to the pixel below.

The differential current sensor further comprises two pairs of comparator 30 circuits 1750A-1750B and 1750C-1750D, one pair 1750A-1750B for determining the edge condition, denoted E_x , between two pixels in the same row (in this case between the current pixel and the pixel on its right), the other pair 1750C-1750D for determining the edge condition, denoted E_y , between two pixels in the same column (in this case between the current pixel and the pixel on top). Each comparator circuit has one input 35 connected to a non-scaled output 1710, 1730 or scaled output 1725, 1745 of the current mirror and a second input connected to a non-scaled output (supplying current i_{i1r}, i_{i1u}) or scaled output (supplying current i_{iKr}, i_{iKu}) of the current mirror of the pixel

on the right or of the pixel on top. In this example, the outputs of each pair of comparator circuits are additionally combined by means of a logic NAND gates 1765, 1775 to provide a corresponding edge condition.

5 The output of one current comparator 1750A of the first pair is also combined by means of a logic NAND gate 1770 with the output of one current comparator 1750C of the second pair to provide an additional information about the intensity difference (denoted "COLOR" and referenced C) of the pixel as compared to the adjacent pixels, in this case as compared to the pixel on the right or the pixel on top.

10 According to U.S. Patent No. 5,703,356, the two edge conditions Ex, Ey and the additional information C are thus defined mathematically by the following Boolean expressions :

$$\begin{aligned} \text{Ex} = & \text{Intensity[pixel]} > K \text{Intensity[pixel on right]} \\ & \text{OR} \end{aligned} \quad (2)$$

15 $K \text{Intensity[pixel]} < \text{Intensity[pixel on right]}$

$$\begin{aligned} \text{Ey} = & \text{Intensity[pixel]} > K \text{Intensity[pixel on top]} \\ & \text{OR} \\ & K \text{Intensity[pixel]} < \text{Intensity[pixel on top]} \end{aligned} \quad (3)$$

20 $\begin{aligned} \text{C} = & \text{Intensity[pixel]} > K \text{Intensity[pixel on right]} \\ & \text{OR} \\ & \text{Intensity[pixel]} > K \text{Intensity[pixel on top]} \end{aligned}$

25 The outputs of the NAND gates 1765, 1770, 1775 are further connected to latch elements 1760A, 1760B and 1760C for at least temporarily storing the corresponding previous results, oEx, oEy and oC designating the previous outputs of the NAND gates 1765, 1770, 1775.

30 An alternative to the solution of Figure 1 consists in providing, for each pixel, an integrating circuit, a scaling amplifier and an adequate number of comparator circuits. Figure 2 schematically shows an example of such an alternative solution. In this example, the current i_{out} generated by the photosensitive element 1000 of the pixel is applied on a input of an integrating circuit 1100 in order to generate an output voltage V_{out} . As illustrated in Figure 3, the integrating circuit 1100 typically consists of an operational amplifier 1110 and a capacitive element 1120 having a determined 35 capacitance C, the capacitive element 1120 being connected between the output and the inverting input of the amplifier 1110, the photosensitive element 1000 being

connected to the inverting input of the amplifier and the non-inverting input of the amplifier being tied to a reference potential such as ground. The integrating circuit 1100 accordingly outputs a voltage signal V_{out} , or integrated signal, which varies over time and which is in essence the result of the integration over time of the current signal 5 i_{out} . Assuming that current i_{out} has a substantially constant value during the period where integrating circuit is active (i.e. during a so-called integration period), the output voltage V_{out} will vary substantially linearly over time.

The voltage signal V_{out} is applied to a first input of two comparator circuits 1300A, 1300C and on the input of a scaling amplifier 1200. This scaling amplifier 1200 10 is designed to output a voltage signal which is a scaled image, denoted KV_{out} , of signal V_{out} . The non-scaled voltage signals, denoted V_{1r} and V_{1u} , from the pixel on the right and the pixel on top, are respectively applied to a first input of two additional comparator circuits 1300B and 1300D. The scaled voltage signal KV_{out} supplied by the scaling amplifier 1200 is applied on the second input of these two comparator 15 circuits 1300B and 1300D. Similarly, the scaled voltage signals, denoted KV_r and KV_u , from the pixel on the right and the pixel on top, are respectively applied to a second input of comparator circuits 1300A and 1300C.

Similarly to the example of Figure 1, NAND gates 1400A, 1400B and 1400C are provided to logically combine the outputs of the comparator circuits in order to 20 generate the edge conditions E_x , E_y and the additional information C .

One serious disadvantage of the two examples illustrated in Figures 1 and 2 resides in the fact that they both require specific circuitry for generating the scaled image of the signal outputted by the photosensitive elements. This circuitry thus reduces the available die area and increases the power consumption and complexity 25 of the sensing device.

An additional disadvantage of the above two examples resides in the fact that one has very little control on the scaling factor K of the circuit. Once this scaling factor is defined during fabrication by an adequate choice of the dimensions of the corresponding electronic components, this scaling factor cannot be adjusted by the 30 user.

It addition, according to the prior art solution, the scaling factor K is typically adjusted so that the sensing device is less sensitive to analog measurement noise. In practice, it would be desirable to implement a hysteresis function in the sensing device. According to the prior art solution, one would again have little control and 35 adjustment capability of this hysteresis function.

Accordingly, it is an object of the present invention to provide a solution that requires less die area, allows power consumption to be decreased, and the architecture of the sensing device to be simplified.

It is another object of the present invention to provide a solution that shows

5 greater flexibility and in particular, that allows adjustment of the scaling factor K and/or easy implementation of a hysteresis function.

SUMMARY OF THE INVENTION

According to a first aspect of the invention, there is provided a method for comparing light intensity between pixels of a photodetector array, each of the pixels comprising a photosensitive element generating a sensed output signal in response to

10 radiation, this method comprising the steps of :

integrating the sensed output signals over time to provide an integrated signal for each of the photosensitive elements ;

interrupting the integration of a first sensed output signal of a first pixel at the end of a first time period and storing the resulting first integrated signal ;

15 continuing the integration of a second sensed output signal of a second pixel until the end of a second time period to provide a second integrated signal ; and

comparing the first and second integrated signals to provide an output signal representative of an edge condition between the first and second pixels.

According to a second aspect of the invention, there is also provided a sensing

20 device for an optical pointing device comprising a plurality of pixels including a first and a second pixel aligned along a first axis, each one of the pixels comprising :

a photosensitive element for generating a sensed output signal in response to radiation ; and

25 an integrating circuit connected to the photosensitive element for integrating the sensed output signal over time and for outputting a resulting integrated signal,

the sensing device further comprising first comparator means for comparing light intensity between the first and second pixels and for determining if a first edge condition exists between the first and second pixels,

30 wherein the first comparator means comprise a first comparator circuit having one comparator input connected to the integrating circuit of the first pixel and another comparator input connected to the integrating circuit of the second pixel,

the sensing device further comprising :

means for resetting the integrating circuits during a resetting period and for releasing these integrating circuits during an integration period ;

means for disconnecting a first comparator input of the first comparator circuit from the corresponding integrating circuit at the end of a first time period ;

means for storing the resulting integrated signal on the disconnected first comparator input of the first comparator circuit ; and

5 means for latching the first comparator circuit at the end of the integration period.

According to a preferred aspect of the invention, there is provided a method and sensing device as defined above, wherein the integration period of the second pixel output signal has a first duration or a second duration shorter than the first

10 duration depending on a previous state of the comparator circuit output. According to this preferred aspect of the invention, a hysteresis function is implemented. According to a specific embodiment, the second duration of the integration period may be selected to be equal to the duration of the first time period during which the first pixel output signal is integrated.

15 An optical pointing device including the above sensing device is also the object of the present invention.

According to the present invention, a time-based scaling scheme is implemented thereby allowing the scaling circuits of the prior art to be eliminated. As a consequence, die area as well as power consumption and complexity is reduced. In 20 addition, the scaling factor may simply be adjusted by changing the ratio between the first time period and second time period (also referred to as integration period).

Furthermore, this time-based scaling scheme may easily be adapted to implement a hysteresis function that allows sensitivity to noise to be reduced.

25 Level detection means may be provided for detecting when a first one of the integrated signals generated by the pixel integrating circuits reaches at least first and second determined levels. Accordingly, the first and second time periods are defined by the time for the first one of the integrated signals to reaches these first and second levels. In this case, this time-based scaling scheme also allows time-division to be used to separate analog and digital circuit operations, and in particular inhibit the clock 30 signal supplied to processing means of the optical pointing device. This clock signal inhibition during analog measurement (i.e. during the integration period) eliminates digital impact (coupling, noise) to analog operations, thereby minimizing analog circuit errors and maximizing system sensitivity.

35 Last but not least, the above solution allows to maximise contrast over the area of the die since the integrating circuits will run until the integrated signal of the brightest pixel of the photodetector array reaches the maximum integration level. The

integration time will therefore be dependent on the illumination level, and contrast, for a given illumination level, is always maximized.

Contrast ratio sensing may also easily be implemented by testing all pixels, upon the end of integration, via an analog circuit to detect the minimum integration 5 level. This provides a measurement of the actual signal contrast seen by the sensor array.

Other aspects, features and advantages of the present invention will be apparent upon reading the following detailed description of non-limiting examples and embodiments made with reference to the accompanying drawings.

BRIEF DESCRIPTION OF THE DRAWINGS

10 - Figure 1 schematically shows a differential current sensor of the prior art for determining an edge condition between pairs of pixels ;
- Figure 2 schematically shows a differential voltage sensor of the prior art for determining an edge condition between pairs of pixels ;
- Figure 3 is a schematic illustration of an integrating circuit used in the 15 differential voltage sensor of Figure 2 ;
- Figure 4 is a schematic block diagram of an optical pointing device ;
- Figure 5 is a schematic representation of the sensing device's photodetector array and pixel architecture ;
- Figure 6A schematically shows a first embodiment of the sensing device 20 according to the present invention ;
- Figure 6B schematically shows a second embodiment of the sensing device according to the present invention ;
- Figure 7 is a schematic representation of a comparator circuit implementing the time-based principle of the present invention ;
25 - Figure 8 is a diagram illustrating the evolution as a function of time of the integrated signals outputted by the integrating circuits of two pixels as well as the evolution as a function of time of the integrated signal outputted by the brightest pixel of the array ;
- Figure 9 is a schematic representation of level detection means for outputting 30 timing signals for controlling the operations of the pixel circuitry ;
- Figure 10 shows three pixels of the photodetector array and their respective edge conditions .
- Figure 11 is a schematic representation of means for implementing a hysteresis function for each comparator circuit ,

THERION INVENTION

- Figure 12 is a third embodiment of a sensing device according to the present invention ; and

- Figure 13 is a schematic representation of an advantageous filtering principle used to sum the output signals of several pixels prior to comparison.

DETAILED DESCRIPTION OF THE INVENTION

5 Figure 4 is a generalized schematic bloc diagram of an optical pointing device in accordance with the present invention. It comprises a photodetector array 420 including a plurality of pixels, this photodetector array 420 being connected to processing means 400 which consists, in a non limiting manner, of a micro-controller, microprocessor or other adequate logic circuitry for processing the signals outputted
10 by the photodetector array 420. As schematically illustrated in Figure 5, the photodetector array 420 is for instance a regular array, preferably square, having M pixel rows (parallel to axis x) and N pixel columns (parallel to axis y). A typical configuration is for instance a 15 x 15 pixels array. Each pixel of the photodetector array 420, designated by reference numeral 4000, essentially includes a
15 photosensitive area 1000 forming a photodiode (or alternatively a phototransistor) and active circuitry 4500 including preamplifier means and comparator circuits for determining edge conditions between the pixel and at least one of his neighbours. This pixel active circuitry 4500 will be described hereafter in more detail.

According to a preferred embodiment of the invention, processing of the edge
20 information determined by each pixel is done outside of the photodetector array, each pixel transmitting its edge conditions to processing means 400. This allows to reduce the size of the pixel active circuitry and thereby increase the photosensitive area of each pixel for greater sensitivity. This also allows to substantially reduce the pixel array wiring. Within the scope of the present invention, it may however perfectly be
25 envisioned to undertake part of the processing in each pixel, such as the determination of the "move-up", "move-down", "move-left" and "move-right" information, as proposed in U.S. Patent No. 5,288,993 and U.S. Patent No. 5,703,356.

Referring again to Figure 4, the optical pointing device further comprises at least one light source 410 (or more) such as a LED, which produces radiation,
30 preferably monochromatic (such as visible or non-visible light – preferably infrared light), that impinges on a portion of a surface S. Again, surface S may be a planar or non-planar surface such as the surface over which the pointing device is moved (as in the case of an optical mouse), the surface of ball (as in the case of an optical trackball) or any other suitable surface that may provide an appropriate intensity pattern for

detection by the photodetector array 420. The optical pointing device typically comprises a window and eventually an optical arrangement (not illustrated) disposed between surface S, on the one hand, and light source 410 and photodetector array 420, on the other hand. These window and optical arrangements are typically

5 designed to protect the optical components of the pointing device from dust and to focus the radiation emitted by light source 410 and the radiation reflected by the illuminated portion of surface S.

The optical pointing device further comprises clock means 430 for supplying a clock signal CLK to processing means 400. This clock signal CLK is used by

10 processing means 400 to derive the necessary timing signals for the digital processing of data and for controlling the operations of photodetector array 420 and pulsing of light source 410. A gating means 435, such as a logic AND gate, is preferably interposed between clock means 430 and processing means 400 to selectively inhibit the supply of clock signal CLK to processing means 400. Activation of this gating
15 means 435 is controlled by processing means 400 via a CLK_CTRL signal. This inhibition of clock signal CLK and its advantages will be explained in more detail in the following. It will be appreciated that clock means 430 is not essential and that clock signal CLK may perfectly be supplied by the host to which the optical pointing device is connected (via the line interface 450).

20 Three switches 441, 442 and 443 further supply additional control inputs to processing means 400. Activation of these switches 441, 442, 443 is typically controlled by means of corresponding buttons located on the device's housing.

Processing means 400 is further adapted to communicate in a bi-directional manner with a line interface 450 that communicates in turn with a host system (not
25 illustrated) over a bus 455. Cursor control signals (and eventually other signals related to the optical pointing device) are supplied to the host system over bus 455.

Processing means 400 may also receive information, such as configuration signals, over bus 455 from the host system.

As briefly mentioned hereinabove, processing means 400 is essentially
30 designed to intermittently sample the pixel outputs of photodetector array 420 in accordance with a defined sequence. The edge information of two successive samples is compared and a relative motion measurement is extracted by processing means 400. The adequate cursor control signals are then derived from the relative motion measurement and transmitted to the host system via line interface 450.

35 According to a preferred embodiment of the present invention, the sensing device further includes level detection means 700 disposed outside of the array 420. Level detection means 700 are designed, on the one hand, to receive the pixel output

signals and monitor the levels of these signals in order to derive specific timing signals for operating the sensing device as this will be apparent from the following. On the other hand, level detection means 700 are also advantageously adapted to detect the minimum level of the pixel output signals.

5 Referring now to Figure 6A, one will describe a first embodiment of a sensing device according to the present invention. For the purposes of explanation, the same detection principle as that disclosed in U.S. Patent No. 5,703,356 will be used in the following, i.e. a detection principle based on comparison of the intensity of the current pixel with the intensities of the pixel on the right and the pixel on top (as schematically 10 illustrated in Figure 10). It will however be appreciated that the detection principle is equally applicable to a single pair of pixels or to more than two pairs of pixels. In addition, it will be appreciated, from reading the following, that the edge conditions are not necessarily defined by the hereinabove expressions (2) to (4).

15 Although Figure 6A only illustrates the active circuitry of a single pixel, it will be appreciated that other pixels of the photodetector array comprise identical circuitry. It will also be appreciated that not every pixel necessarily includes such circuitry. In particular, pixels located on the extreme right and top side of the photodetector array (i.e. pixels which do not have a neighbouring pixel on their right side and/or upper side) would not necessarily require identical comparator means. It will be appreciated 20 however that each pixel will at least include the photosensitive element 1000 and the integrating circuit or preamplifier circuit 1100.

The sensing device of Figure 6A is similar to the sensing device of Figure 2 in that it comprises the photosensitive element 1000 (in this case a reverse biased photodiode), the integrating circuit 1100 for outputting the integrated signal $V_{out}(t)$ 25 representative of the photodiode current i_{out} , and the four comparator circuits 1300A to 1300D. As before, the integrating circuit 1100 may be reset by activation of a RESET signal and released during a determined integration period by deactivation of the RESET signal.

In contrast to the prior solution, the sensing device of Figure 6A does not 30 comprise any scaling amplifier for providing a scaled image of the integrated signal $V_{out}(t)$. According to the present invention, the output of integrating circuit 1100 is connected directly to the second input of comparator circuits 1300B and 1300D. In addition, interrupting means 1250 are interposed between the integrating circuit output 35 and the first input of comparator circuits 1300A and 1300C. These interrupting means 1250 are designed to disconnect (upon activation of a first timing signal $\phi 1$) the first input of comparator circuits 1300A and 1300C from the output of integrating circuit 1100 at the end of a first time period which is shorter than the integration period. The

corresponding interrupting means of the pixel on the right and the pixel on top are operated in a similar manner. The resulting integrated signals at that time may conveniently be stored on the input capacitance of the first input of the comparator circuits. An additional capacitive element or any other suitable storing means, may be

5 connected on the first inputs of the comparator circuits.

As illustrated in Figure 6B, interrupting means 1250 may alternatively be disposed on the first input of each comparator circuit. This would have the advantage of reducing the number of inter-pixel connexions to two connexions (one for the pixel on the left and one for the pixel below) instead of four connexions in the example of

10 Figure 6A. For simplicity, each interrupting means may be implemented as a simple switching transistor, the gate of which is controlled by timing signal $\phi 1$.

Similarly to the prior art solution, the scaled image and non-scaled image of the integrated signal supplied by the pixels located on the right and on top are supplied to comparator circuits 1300A to 1300D. In the example of Figure 6A, the non-scaled

15 images of the integrated signals of the pixel on the right and the pixel on top are designated by references $Vr1$ and $Vu1$, the corresponding scaled images of these signals being designated by references $Vr2$ and $Vu2$. The non-scaled image, designated $Vout1$, and the scaled image, designated $Vout2$, of the integrated signal $Vout(t)$ of the pixel are similarly supplied to the pixel on the left and the pixel below.

20 According to an advantageous embodiment of the present invention which will be described hereinafter in more details, signal $Vout(t)$ is also supplied to additional level detection means outside of the array.

According to the example of Figure 6B, it will be appreciated that the pixel receives directly the output signals $Vr(t)$ and $Vu(t)$ of the pixel on the right and the pixel 25 on top, and supplies its output signal $Vout(t)$ to the pixel on the left and the pixel below.

The logic NAND gates 1400A to 1400C of Figure 2 have not been illustrated in the embodiment of Figures 6A and 6B. As a matter of fact, these logic NAND gates are not absolutely necessary and the four comparator outputs may directly supply their respective edge signals to the processing means. As already mentioned, each

30 comparator circuit 1300A to 1300D individually outputs an edge information. For instance, comparator circuit 1300A outputs a first edge information that may be designated as a first positive edge information $Ex+$, the definition of which is as follows :

35 $Ex+ = \text{Intensity[pixel]} > K \text{ Intensity[pixel on right]} \quad (5)$

Similarly, comparator circuit 1300B outputs a second edge information, which is the complement of first positive edge information Ex_+ , and that may be designated as a first negative edge information Ex_- , the definition of which is as follows :

$$5 \quad \text{Ex-} \quad \text{Intensity[pixel]} > \text{Intensity[pixel on right]} \quad (6)$$

Using the same terminology, comparator circuits 1300C and 1300D respectively output a second positive edge information E_{Y+} and a second negative edge information E_{Y-} the definitions of which are as follows :

$$10 \quad \text{Ey+} = \text{Intensity[pixel]} > K \text{Intensity[pixel on top]} \quad (7)$$

$$E_{V-} = K \text{Intensity[pixel]} > \text{Intensity[pixel on top]} \quad (8)$$

15 Logic gates may nevertheless be provided to logically combine the comparator circuit outputs in the adequate manner. Using the above terminology, it will be appreciated that these logic gates would be logic OR gates in this case.

In addition, it will be appreciated that four distinct comparator circuits are not required. It may be perfectly envisaged to determine the relative motion measurement based on two conditions out of the four conditions above. For instance, post-processing of the edge data may be based only on the above first positive edge information E_{V1} and second positive edge information E_{V2} .

Referring now to Figures 7 and 8, one will now describe the edge detection principle according to the present invention. According to the present invention, a time-based scaling scheme is implemented to detect an edge condition between two pixels. Assuming that the current signals outputted by the photosensitive elements are constant during the integration period, the integrated signals outputted by the integrating circuits will vary in a linear manner over time. As illustrated in Figure 8, a first integrated signal $V1(t)$ of a first pixel and a second integrated signal $V2(t)$ of a second pixel may therefore be illustrated as linear curves. Assuming that the illumination level of these two pixels is different, the slope of these integrated signals will be different. In this case, signal $V1(t)$ varies more strongly over time than signal $V2(t)$, signifying that the first pixel has a greater illumination level than the second pixel.

35 As schematically illustrated in Figure 7, the first and second integrated signals
 V₁(t) and V₂(t) are respectively supplied on first and second inputs of a comparator
 circuit 1300 illustrated as an operational amplifier. An interrupting means 1250 is

disposed on the first comparator input so as to disconnect this first input from the corresponding signal upon activation of timing signal $\phi 1$ (at a time $t1$ following the start of an integration period). After disconnection, the resulting integrated signal is stored on an input capacitance C_{input} of the comparator circuit. The comparator circuit is

5 latched upon activation of a second timing signal $\phi 2$ (at a time $t2$ corresponding to the end of the integration period) to provide the output signal representative of the difference between the signals applied on its two inputs.

Referring to Figure 8, interruption of the integration of the first integrated signal $V1(t)$ at the end of a first time period $t1 - t0$ (this interruption being controlled via the 10 first timing signal $\phi 1$) results in a voltage signal having a first value $V1(t1)$. Continuation of the integration of the second integrated signal $V2(t)$ until the end of a second time period $t2 - t0$, or integration period, (this being controlled by the second timing signal $\phi 2$) results in a voltage signal having a second value $V2(t2)$. Similarly, interruption of the integration of the second integrated signal $V2(t)$ at time $t1$ and 15 continuation of the integration of the first integrated signal $V1(t)$ until time $t2$ result in voltage signals having first and second values $V2(t1)$ and $V1(t2)$. It will be appreciated that the ratio between these second and first values corresponds to the scaling factor K and is determined by the ratio between the second and first integration periods. The relationship between the scaling factor, the first and second values and the first and 20 second time periods $t1 - t0$ and $t2 - t0$ may be summarized as follows :

$$K = V1(t2)/V1(t1) = V2(t2)/V2(t1) = (t2 - t0)/(t1 - t0) \quad (9)$$

Assuming that integrated signal $V1(t)$ corresponds to the output signal $Vout(t)$ 25 of Figure 6A or 6B and integrated signal $V2(t)$ corresponds to the output signal of the pixel on the right, it will be appreciated that comparator circuit 1300A would in this case detect a first positive edge $Ex+$.

According to the present invention, the scaling factor K is simply determined by the ratio between the first and second time periods. Adjustment of this scaling factor K 30 can accordingly be easily effected by changing one or both of the first and second time periods.

The ratio between the second and first time periods can be controlled via the processing means. A first solution simply consists in activating the interrupting means 1250 of each pixel at time $t1$ (thereby disconnecting the first input of every comparator circuits of the photodetector array) followed by the activation of the comparator circuits 35 at time $t2$, instants $t1$ and $t2$ being directly derived from the clock signal CLK .

Preferably, instants t_1 and t_2 (i.e. timing signals ϕ_1 and ϕ_2) are not derived from the clock signal CLK, but are determined using the level detection means 700 of Figure 4 that monitor the level of the integrated signals of all pixels. Such level detection means 700 are schematically illustrated in Figure 9. The purpose of level detection means 700 is to monitor the level of the integrated signals of all pixels and detect when the first one of these integrated signals (i.e. the signal of the brightest pixel in the photodetector array) reaches first and second levels. As illustrated in Figure 8, first and second levels V_{t1} and V_{t2} ($=V_{max}$) are defined, and the integrated signals of the brightest pixel in the array, designated $V_{out,max}(t)$, is detected by level detection means 700. The first time period $t_1 - t_0$ is thus defined by the time taken by integrated signal $V_{out,max}(t)$ to reach the first level V_{t1} . Similarly, the second time period $t_2 - t_0$ is defined by the time taken by integrated signal $V_{out,max}(t)$ to reach the second level V_{t2} .

One advantage of level detection means, resides in the fact that contrast will be maximized since integration is continued until the integrated signal of the brightest pixel in the array reaches the second level (or maximum integration level) V_{t2} . Another advantage of these level detection means resides in the fact that the digital and analog operations of the sensing device may be separated, that is the clock signal CLK may be inhibited during the integration period, since timing is derived from the evolution of the maximum integrated signal $V_{out,max}(t)$. Indeed, referring again to Figure 4, the gating means 435 may be deactivated during the integration period (CLK_CTRL at a low logic state), thereby inhibiting the supply of clock signal CLK to the processing means, and be reactivated upon the end of the integration period. This inhibition of the clock signal during analog measurement (i.e. during the integration period) eliminates digital impact (coupling, noise) to analog operations, thereby minimizing analog circuit errors and maximizing system sensitivity.

Contrast ratio sensing may also easily be implemented using the level detection means. In this case, level detection means 700 may be adapted to test all pixels upon the end of integration and to provide a measurement of the minimum integration level, designated $V_{out,min}$. This measurement $V_{out,min}$ may be converted to a digital word and transmitted to the host system to provide a measurement of the actual signal contrast seen by the sensor array.

Referring again to Figure 8, the time-based principle used according to the present invention may further be adapted to implement a hysteresis function. This can easily be achieved by defining a third time period $t_{2hyst} - t_0$ (or second integration period) which is shorter than the integration period $t_2 - t_0$. This can either be achieved by defining a third instant t_{2hyst} or, referring to the level detection means of Figure 9,

by defining a third level $Vt2hyst$ and detecting when the first one of the integrated signals reaches this level, level detection means 700 supplying a third timing signal designated $\phi2hyst$.

Referring to Figure 11, the comparator circuits may be adapted so as to

- 5 selectively apply timing signals $\phi2$ or $\phi2hyst$ depending on the state of the previous comparator output signal. To this end, a latch element 1310 (such as a conventional S-R flip-flop) can be provided on the comparator circuit output in order to supply a signal representative of the previous state of the comparator output signal (i.e. a signal indicating whether or not an edge was previously detected). As schematically
- 10 illustrated in Figure 11, timing signal $\phi2hyst$ is selected if an edge was detected on the previous sample. Timing signal $\phi2$ is otherwise selected if an edge was not detected on the previous sample. Selection of the adequate timing signal may easily be achieved using a conventional two-input multiplexing circuit 1350 which is controlled by the output signal Q of the latch element 1310.

- 15 It will be appreciated that the second integration period $t2hyst-t0$ may be selected to be equal to the first time period $t1-t0$. In this case, timing signal $\phi2hyst$ would in effect correspond to timing signal $\phi1$. This specific implementation is used in the embodiment of Figure 12.

Having described the invention with regard to certain specific embodiments, it

- 20 is to be understood that these embodiments are not meant as limitations of the invention. Indeed, various modifications and/or adaptations may become apparent to those skilled in the art without departing from the scope of the annexed claims. For instance, the proposed embodiments are not necessarily limited to sensing devices comprising a regular array of pixels aligned along two orthogonal axes. Other pixel
- 25 arrangements may be envisaged, such as pixel arrangements including pixels aligned along two (or more) non orthogonal axes.

In addition, as already mentioned hereinabove, the sensing device according to the present invention does not necessarily include four distinct comparator circuits for providing suitable edge conditions information. In the case of a sensing device

- 30 comprising a photodetector array including pixels aligned along first and second axes, at least one comparator per axis would be sufficient as illustrated in the embodiment of Figure 12 which implements a hysteresis function wherein time $t2hyst$ is selected to be equal to $t1$. The sensing device of Figure 12 only comprises two comparator circuits 1300, 1300', one for providing a first edge condition between two pixels aligned along a first axis (in this case the current pixel and the pixel on its right) and the other one for providing a second edge condition between two pixels aligned along the second axis (in this case the current pixel and the pixel below). It will be appreciated that the
- 35

embodiment of Figure 12 also differs from the embodiments of Figures 6A and 6B in that it supplies its output signal to the pixel on its left and the pixel on top and receives the output signal of the pixels on its right and below.

Finally, it will also be appreciated that each comparator input may be

- 5 connected to more than one photosensitive element. For instance, the output signals of four adjacent pixels may be summed so as to create a "filtered" pixel as schematically illustrated in Figure 13. An advantage of this filtering principle resides in the fact that it reduces high frequency spatial signals due to the randomness of the illuminated surface. This filtering principle is also the object of another pending
- 10 application filed concurrently with this one.